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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named
Inventor : David W. Duquette

Appln. No. : 09/767,199

Filed : January 22, 2001

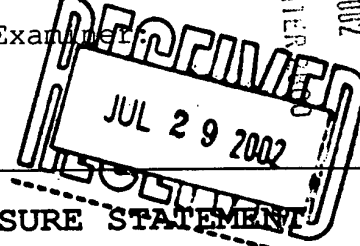
For : IMPROVED LASER ALIGN SENSOR
WITH SEQUENCING LIGHT
SOURCES

Docket No.: C34.12-0021

Group Art Unit: 2877

Examiner:

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231

I HEREBY CERTIFY THAT THIS PAPER IS BEING
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WASHINGTON, D.C. 20231, THIS

15th DAY OF July, 2002.

PATENT ATTORNEY

Sir:

The patents or publications listed on the enclosed PTO Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of the patents or publications cited are enclosed.

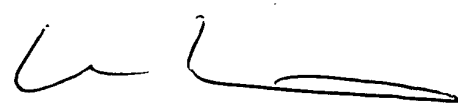
Submitted herewith is a copy (with English translation as appropriate) of an Official Search Report of the European Patent Office in counterpart foreign application No. PCT/US02/00302 filed January 8, 2002.

The Director is authorized to charge any fee deficiency required by this paper or credit any overpayment to Deposit Account No. 23-1123.

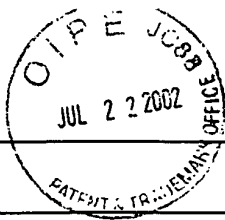
Respectfully submitted,

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FORM PTO-1449	Atty. Docket No.: C34.12-0021	Appl. No.: 09/767,199
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor:	
	David W. Duquette	
	Filing Date	Group Art:
	January 22, 2001	2877

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	5,687,475	11/18/97	Doemens	29	833	
AB						
AC						
AD						
AE						
AF						
AG						
AH						
AI						
AJ						

FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AK	WO 97/30572	08/21/97	WIPO			X
AL						
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AN						

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.